

Room A			
8:45	Opening Remark		
9:00	Keynote Lecture I: Comprehensive SiP Enabling New System Integration CP Hung, ASE Group Chairs: Y. Orii, Nagase, S. Hayashida, ASE Group		
10:00	Break		
10:10	Room A	Room B	Room C
10:10	<b>WA1: Heterogeneous Integration Roadmap-1</b> Chairs: Y. Orii, Nagase, S. Aoki, Lintec <b>WA1-1 &lt;Session Invited&gt;</b> HIR Overview Wilmer R Bottoms, 3MT Solutions / USA <b>WA1-2 &lt;Session Invited&gt;</b> Beyond Scaling - Trends in AI Hardware R&D Dale McHerron, IBM Research / USA <b>WA1-3 &lt;Session Invited&gt;</b> Organic Interposer (CoWoS-R) Technology Shin-Puu Jeng, TSMC / Taiwan <b>WA1-4 &lt;Session Invited&gt;</b> Advanced Packaging : Road Mapping the Future Ravi Vithal Mahajan, Intel / USA	<b>WB1: Interconnections-1</b> Chairs: M. Fujino, AIST, H. Ohkuma, HTO <b>WB1-1</b> Pressureless and Low Temperature Direct Bonding on Si, SiC and GaN via Ag Paste Sinter-joining Zheng Zhang, Chuantong Chen, Aiji Suetake, Ming-Chun Hsieh, Aya Iwaki, Katsuaki Suga, Osaka University / Japan <b>WB1-2</b> Cobalt-Tin Intermetallic Compounds as Alternative Surface Finish for Low Temperature Die-to-Wafer Solder Stacking Fumihiko Inoue, Jaber Derakhshandeh, Carine Gerets, Eric Beyne, imec / Belgium <b>WB1-3</b> Photonic Sintering of Composite Pastes with Copper Oxide Powders Using Different Light Sources Wei-Han Cheng <sup>1</sup> , Po-Hsiang Chiu <sup>1</sup> , Yan-Jie Li <sup>1</sup> , Ming-Tsang Lee <sup>2</sup> , Kiyokazu Yasuda <sup>3</sup> , Jenn-Ming Song <sup>1,3</sup> , National Chung Hsing University, National Tsing Hua University / Taiwan, Osaka University / Japan (11:25)	<b>WC1: Emerging Technologies-1</b> Chairs: N. Fujimori, Olympus Medical Systems, T. Kasahara, Hosei University <b>WC1-1</b> Fabrication of Micropatterned Fish Scale Collagen Scaffold Using Soft Lithography for Oral Mucosa Tissue Engineering Kazuma Kishimoto <sup>1</sup> , Keito Miwa <sup>1</sup> , Ayako Suzuki <sup>2</sup> , Isamu Yamaguchi <sup>3</sup> , Yoshihiro Kodama <sup>3</sup> , Orakarn Suebsamarn <sup>2</sup> , Shuichi Shoji <sup>1</sup> , Kenji Izumi <sup>2</sup> , Jun Mizuno <sup>1,4</sup> , Waseda University, Niigata University, Taki Chemical, Suwa University of Science / Japan <b>WC1-2</b> Battery Less Soil Moisture Sensors for Strawberry Seedlings Haruichi Kanaya <sup>1</sup> , Osamu Takiguchi <sup>2</sup> , Shunsuke Uto <sup>3</sup> , Katsumi Shimomura <sup>3</sup> , Kyushu University, ASENS, Fukuoka Agriculture and Forestry Research Center / Japan <b>WC1-3</b> Ni coated Cu Foils as the Substrate for Flexible Piezocomposite Power Generators Chi-Hsuan Lin <sup>1</sup> , Jun-Hao Lee <sup>1</sup> , Chia-Che Wu <sup>2</sup> , Jenn-Ming Song <sup>1</sup> , National Chung Hsing University, National Chung Hsing University / Taiwan <b>WC1-4</b> MCU and Motor Driver Leaf Modules of Coin-Sized PCBs in an Open-Innovation IoT/CPS Platform Kenichi Agawa <sup>1</sup> , Tokihiko Mori <sup>2</sup> , Ryoji Ninomiya <sup>1</sup> , Minoru Takizawa <sup>1</sup> , Takayasu Sakurai <sup>2</sup> , Toshiba Electronic Devices & Storage, The University of Tokyo / Japan
11:50	Lunch Time		
12:40	Keynote Lecture II: Future View: technology merger strengthens evolution of semiconductor chips in the hyper-scaling AI/ML era Kazuya Okamoto, Yamaguchi University / Osaka University Chairs: A. Shigetou, NIMS, Y. Kanechika, Tokuyama		
13:40	Break		
13:50	Room A	Room B	Room C
13:50	<b>WA2: Heterogeneous Integration Roadmap-2</b> Chair: Y. Orii, Nagase <b>WA2-1 &lt;Session Invited&gt;</b> Introduction to HIR Workshop Session William Chen, ASE / USA (14:00) <b>WA2-2 &lt;Session Invited&gt;</b> Heterogeneous Integration for HPC and Data Centers Kanad Ghose, SUNY-Binghamton, Dale Becker, IBM / USA (14:20) <b>WA2-3 &lt;Session Invited&gt;</b> Photonics TWG update Amr S Helmy, University of Toronto / Canada (14:40) <b>WA2-4 &lt;Session Invited&gt;</b> Wafer Level and Panel Level Packaging John Hunt, ASE / USA (15:00) <b>WA2-5 &lt;Session Invited&gt;</b> Overview of the Co-Design Chapter Jose Schutt Aine, University of Illinois / USA (15:20) <b>WA2-6 &lt;Session Invited&gt;</b> HIR Workshop Session Wrap-up Tom Salmon, SEMI / USA	<b>WB2: Interconnections-2</b> Chairs: K. Yasuda, Osaka University, K. Hirano, Panasonic <b>WB2-1</b> Reliable Joint Material by Sn-Cu-Ni IMC Fine Particles Shigenobu Sekine <sup>1</sup> , Hiroaki Ikeda <sup>1</sup> , Shigeo Arai <sup>2</sup> , Napra, Nagoya University / Japan <b>WB2-2</b> A Technique to Mount Narrow-Pitch Micro Solder Balls Shunichi Haraguchi <sup>1</sup> , Chisato Oyama <sup>1</sup> , Kotaro Usuda <sup>2</sup> , Hideki Ikeda <sup>1</sup> , KOMORI, SERIA ENGINEERING / Japan <b>WB2-3</b> Voidless Chip-on-Wafer Process for Functional Interposer Yoshiaki Satake <sup>1,2</sup> , Tatsuya Funaki <sup>1,2</sup> , Kyosuke Kobinata <sup>1,3</sup> , Youngsuk Kim <sup>1,3</sup> , Takayuki Ohba <sup>1</sup> , Tokyo Institute of Technology, Murata Manufacturing, DISCO / Japan (15:05)	<b>WC2: Emerging Technologies-2</b> Chairs: N. Fujimori, Olympus Medical Systems, T. Nonaka, Huawei Technologies Japan <b>WC2-1 &lt;Session Invited&gt;</b> Industry 4.0 Adoption: A Journey in Smart Supply Chain and Manufacturing Transformation Feng Xue, IBM / Singapore <b>WC2-2</b> Development of Power Management System for RF Energy Harvester Masaya Murakami <sup>1</sup> , Mohamed M. Mansour <sup>2</sup> , Shota Torigoe <sup>2</sup> , Shuya Yamamoto <sup>2</sup> , Haruichi Kanaya <sup>2</sup> , SEIKO ELECTRIC, Kyushu University / Japan <b>WC2-3</b> Silicon-Photonics-Embedded Interposers and Their Applications Koichi Takemura <sup>1</sup> , Daisuke Ohshima <sup>1</sup> , Akihiro Noriki <sup>1,2</sup> , Daisuke Okamoto <sup>1</sup> , Akio Ukita <sup>1</sup> , Jun Ushida <sup>1</sup> , Masatoshi Tokushima <sup>1</sup> , Daisuke Shimura <sup>1</sup> , Tsuyoshi Aoki <sup>1</sup> , Takeru Amano <sup>1,2</sup> , Photonics Electronics Technology Research Association, National Institute of Advanced Industrial Science and Technology / Japan <b>WC2-4</b> A High-Sensitivity Olfactory System with a Graphene FET Biosensor and a Portable Odorant Capture Module Hideyuki Tomizawa <sup>1</sup> , Kou Yamada <sup>1</sup> , Hiroshi Hamasaki <sup>1</sup> , Yoshiaki Sugizaki <sup>1</sup> , Miyuki Tabata <sup>2</sup> , Yuji Miyahara <sup>2</sup> , Atsunobu Isobayashi <sup>1</sup> , Toshiba, Tokyo Medical and Dental University / Japan
15:30	Break		
15:40	Room A	Room B	Room C
15:40	<b>WA3: Thermal Management</b> Chairs: H. Sakamoto, Huawei Technologies Japan, T. Hatakeyama, Toyama Prefectural University <b>WA3-1 &lt;Session Invited&gt;</b> Possibility of Next Innovation of Forced Convection Cooling in High-Density Packaging Electronic Equipment by Pulsating Flow Phenomena from Knowledge of Nature Takashi Fukue, Kanazawa Institute of Technology / Japan <b>WA3-2</b> Low Pressure Subcooled Boiling in a Compact Vessel for Cooling Technology Noriyuki Unno, Kazuhisa Yuki, Risako Kibushi, Koichi Suzuki, Sanyo-Onoda City University / Japan <b>WA3-3</b> Parameter Identification of Distributed Thermal Network for Surface Mount Type Power Semiconductor Packages Koji Nishi, Ashikaga University / Japan <b>WA3-4</b> Room-Temperature Bonding of AlN Ceramic and Si Semiconductor Substrates for Improved Thermal Management Takashi Matsumae <sup>1</sup> , Yuichi Kurashima <sup>1</sup> , Hideki Takagi, Kazunori Nishizono <sup>2</sup> , Tsutomu Amano <sup>2</sup> , Eiji Higurashi <sup>1</sup> , National Institute of Advanced Industrial Science and Technology, MARUWA / Japan	<b>WB3: Interconnections-3</b> Chairs: T. Aoki, IBM Japan, Y. Morikawa, Ulvac <b>WB3-1</b> Low Temperature Bonding of Cu Bump to WBG Device Using the Surface Activation Method Tadatomo Suga <sup>1</sup> , Kai Takeuchi <sup>1</sup> , Seongbin Shin <sup>1</sup> , Nora Martinez <sup>1</sup> , Yoshinari Ikeda <sup>2</sup> , Akira Hirao <sup>2</sup> , Motohito Hori <sup>2</sup> , Meisei University, Fuji Electric / Japan <b>WB3-2</b> Surface Activated Bonding of Nb-Nb for Superconducting Device Interconnect Yuta Takahashi <sup>1,2</sup> , Masahisa Fujino <sup>2</sup> , Takashi Matsumae <sup>3</sup> , Hiroshi Nakagawa <sup>2</sup> , Katsuya Kikuchi <sup>2</sup> , Tohru Taino <sup>1</sup> , Saitama University, National Institute of Advanced Industrial Science and Technology / Japan <b>WB3-3</b> Effects of Surface Physical Properties on Ultrasonic Cu/Cu Bonding I-You Yu, Liang-Shing Shih, Jenn-Ming Song, National Chung Hsing University / Taiwan (16:55)	<b>WC3: Power Electronics</b> Chairs: Y. Inaba, Denso, T. Onishi, Grand Joint Technology <b>WC3-1</b> Packaging of (650 V, 150 A) GaN HEMT with Low Parasitics and High Thermal Performance Shengchang Lu, Tianyu Zhao, Rolando Burgos, Guo-Quan Lu, Virginia Tech / USA <b>WC3-2</b> Direct Bonding of Diamond and Si Substrates Using NH <sub>3</sub> /H <sub>2</sub> O <sub>2</sub> Cleaning Shoya Fukumoto <sup>1,2</sup> , Takashi Matsumae <sup>2</sup> , Yuichi Kurashima <sup>2</sup> , Hideki Takagi <sup>2</sup> , Hitoshi Umezawa <sup>2</sup> , Masanori Hayase <sup>2</sup> , Eiji Higurashi <sup>2</sup> , Tokyo University of Science, National Institute of Advanced Industrial Science and Technology / Japan <b>WC3-3</b> Low Temperature Bonding of GaN and Carbon Composite via Au Capping Layer Activated by Ar Fast Atom Bombardment Kai Takeuchi <sup>1</sup> , Suga Tadatomo <sup>1</sup> , Atsushi Tanaka <sup>2</sup> , Akio Wakejima <sup>3</sup> , Meisei University, Nagoya University, Nagoya Institute of Technology / Japan (16:55)
17:20			

Room A				
9:00	<b>Keynote Lecture III: Direct Bonding: A New Paradigm Shift in Semiconductor Assembly</b>			
10:00	Belgacem Haba, Xperi			
10:00 10:10	Chairs: O. Suzuki, Namics, N. Tanaka, Showadenko Materials			
Break				
Room A	Room B	Room C		
10:10	<p><b>TA1: iNEMI Session</b> Chairs: Y. Tomita, Intel, H. Yamada, Toshiba</p> <p><b>TA1-1 &lt;Session Invited&gt;</b> 5G Standard Reference Materials Nathan Orloff, National Institute of Standards and Technology / USA</p> <p><b>TA1-2</b> Predictive Modelling Methodologies for Bi-Material Wafer Warpage Kang Eu Ong<sup>1</sup>, Wei Keat Loh<sup>1</sup>, Jenn An Wang<sup>2</sup>, Arvind Purushotaman<sup>3</sup>, Tatsuro Yoshida<sup>4</sup>, Kei Murayama<sup>5</sup>, Makoto Tsukahara<sup>6</sup>, Ron W. Kulterman<sup>7</sup>, Haley Fu<sup>6</sup>, <sup>1</sup>Intel Technology / Malaysia, <sup>2</sup>CoreTech System (Moldex3D) / Taiwan, <sup>3</sup>ANSYS / USA, <sup>4</sup>Shinko Electric Industries / Japan, <sup>5</sup>Flex / USA, <sup>6</sup>iNEMI / China</p> <p><b>TA1-3</b> Voids Inspection Capability Study in First-Level Interconnects for Flip Chip Packages Masahiro Tsuruya<sup>1</sup>, Kor Oon Lee<sup>2</sup>, Kiyoshi Oi<sup>3</sup>, Sze Pei Lim<sup>4</sup>, Yvonne Yeo<sup>5</sup>, Keith Sweatman<sup>6</sup>, Toshiaki Ono<sup>7</sup>, Kei Murayama<sup>3</sup>, Steven R. Martell<sup>1</sup>, Haruo Shimamoto<sup>8</sup>, Evstatin Krastev<sup>7</sup>, <sup>1</sup>iNEMI / Japan, <sup>2</sup>Intel / Malaysia, <sup>3</sup>Shinko Electric Industries / Japan, <sup>4</sup>Indium / Malaysia, <sup>5</sup>IBM / Singapore, <sup>6</sup>Nihon Superior / Australia, <sup>7</sup>Nordson Electronics Solutions / Japan &amp; USA, <sup>8</sup>AIST, Japan</p> <p><b>TA1-4</b> Low Temperature 1st Level Interconnect in Packaging and Its Challenges Sze Pei Lim<sup>1</sup>, Charles Arvin<sup>2</sup>, David Locker<sup>3</sup>, Ravi Pokhrel<sup>4</sup>, Wei Keat Loh<sup>5</sup>, Keith Sweatman<sup>6</sup>, Derek Daily<sup>7</sup>, Naoki Kubota<sup>8</sup>, Masahiro Tsuruya<sup>9</sup>, <sup>1</sup>Indium / Malaysia, <sup>2</sup>IBM, <sup>3</sup>DoD, <sup>4</sup>Dupont / USA, <sup>5</sup>Intel / Malaysia, <sup>6</sup>Nihon Superior / Australia, <sup>7</sup>Senju Metal Industry / USA, <sup>8</sup>Tamura, <sup>9</sup>iNEMI / Japan</p>	<p><b>TB1: Materials and Processing-1</b> Chairs: S. Takyu, Lintec, H. Hozoji, AIST</p> <p><b>TB1-1 &lt;Session Invited&gt;</b> Advanced Thermal Materials and Systems: Technology and Trend Analysis for the Future Yukihiro Kanechika, Kazuya Okamoto, Yamaguchi University / Japan</p> <p><b>TB1-2</b> Characterization of Additively Formed Copper Layer by Blue Laser-Sintered Copper Nanoparticles Kiyokazu Yasuda<sup>1</sup>, Yuki Takada<sup>1</sup>, Jenn-Ming Song<sup>1,2</sup>, <sup>1</sup>Osaka University / Japan, <sup>2</sup>National Chung Hsing University / Taiwan</p> <p><b>TB1-3</b> Die-attach Properties of Pressure-sintered Copper Joints on Adhesive Metallization Surfaces in N<sub>2</sub> Atmosphere Dai Ishikawa<sup>1</sup>, Bao Ngoc An<sup>2</sup>, Matthias Mail<sup>2</sup>, Helge Wurst<sup>2</sup>, Benjamin Leyrer<sup>2</sup>, Thomas Blank<sup>2</sup>, Marc Weber<sup>2</sup>, Hideo Nakako<sup>1</sup>, <sup>1</sup>Showa Denko Materials / Japan, <sup>2</sup>Karlsruhe Institute of Technology / Germany</p> <p><b>TB1-4</b> Fine Pitch Bumping and Flip Chip Joining with Sn-Bi Based Solders by Injection Molded Solder Technology Toyohiro Aoki<sup>1</sup>, Katsuhiko Yoshida<sup>2</sup>, Koki Nakamura<sup>2</sup>, Takashi Hisada<sup>1</sup>, Kojo Fujimoto<sup>3</sup>, Shinji Fukumoto<sup>2</sup>, <sup>1</sup>IBM Japan, <sup>2</sup>Osaka University / Japan</p>	<p><b>TC1: Advanced Interface</b> Chairs: J. Mizuno, Waseda University, T. Matsunaga, Tottori University</p> <p><b>TC1-1 &lt;Session Invited&gt;</b> Hybrid Bonding Without Vacuum and High Temperature for Cross-Cutting Applications Akitsu Shigetou, National Institute for Materials Science / Japan</p> <p><b>TC1-2 &lt;Session Invited&gt;</b> Metasurface Quantum-Well Infrared Photodetectors Hideki T. Miyazaki, National Institute for Materials Science / Japan</p> <p><b>TC1-3 &lt;Session Invited&gt;</b> High-Performance SAW Devices Using Bonded Dissimilar-Material Structures Shoji Kakio, University of Yamanashi / Japan</p> <p><b>TC1-4 &lt;Session Invited&gt;</b> Fabrication and Characterization of Microfluidic Electrogenerated Chemiluminescence Devices Takashi Kasahara<sup>1</sup>, Jun Mizuno<sup>2</sup>, <sup>1</sup>Hosei University, <sup>2</sup>Waseda University / Japan</p>	
11:50				
11:50 12:40	<b>Lunch Time</b>			
12:40	<b>Poster Session</b>			
13:40 13:50	<b>Break</b>			
Room A	Room B	Room C		
13:50	<p><b>TA2: LED Technologies</b> Chairs: K. Ichikawa, Nichia, A. Okuno, Green Planets</p> <p><b>TA2-1 &lt;Session Invited&gt;</b> Medical Study of 400-410nm LED and micro LED Atsushi Okuno, Green Planets / Japan</p> <p><b>TA2-2 &lt;Session Invited&gt;</b> 2MGy High Radiation Tolerance LED &amp; UVC LED Packaging Tetsuya Onishi, Grand Joint Technology / Hong Kong</p> <p><b>TA2-3 &lt;Session Invited&gt;</b> Ultrafast Laser Transfer Technology Yoshiyuki Arai, Toray Engineering / Japan</p> <p><b>TA2-4 &lt;Session Invited&gt;</b> Fluidic Assembly of microLED Displays Paul Schuele, eLux / USA</p>	<p><b>TB2: Materials and Processing-2</b> Chairs: Y. Kanechika, Tokuyama, K. Shibayama, Sekisui Chemical</p> <p><b>TB2-1</b> Effect of Sequential Plasma Activation on Al<sub>2</sub>O<sub>3</sub> for Low Temperature Bonding of Glass Kai Takeuchi, Tadatomu Suga, Meisei University / Japan</p> <p><b>TB2-2</b> Low-temperature Printable and Stretchable Circuit Board and Its Application to Flexible Hybrid Electronics Teppei Araki<sup>1,2</sup>, Yusuke Okabe<sup>2</sup>, Naoko Kurihira<sup>1</sup>, Yuko Kasai<sup>1,2</sup>, Yuki Noda<sup>1</sup>, Tsuyoshi Sekitani<sup>1,2</sup>, <sup>1</sup>Osaka University, <sup>2</sup>AIST-Osaka University, <sup>3</sup>CEMEDINE / Japan</p> <p><b>TB2-3</b> X-ray Radiolysis-Induced-Photochemical Reaction at Interface Between Liquid and Substrate S. Saegusa<sup>1</sup>, N. Akamatsu<sup>1</sup>, I. Sakurai<sup>2</sup>, I. Okada<sup>3</sup>, Y. Utsumi<sup>1</sup>, A. Yamaguchi<sup>1</sup>, <sup>1</sup>University of Hyogo, <sup>2</sup>Nagoya University, <sup>3</sup>Aichi Synchrotron Radiation Center / Japan</p> <p><b>TB2-4</b> Analysis of Low Friction Force and Low Contact Resistance Film Using Sn-Cu Plating Hiroki Hayashi<sup>1,2</sup>, Naohiro Takaine<sup>1</sup>, Hiroyuki Funasaki<sup>1</sup>, Mitsuhiro Watanabe<sup>2</sup>, <sup>1</sup>TAKAMATSU Plating, <sup>2</sup>Kanto Gakuin University / Japan</p>	<p><b>TC2: Quality, Modeling, and Reliability</b> Chairs: K. Yasuda, Osaka University, H. Sakamoto, Huawei Technologies Japan</p> <p><b>TC2-1</b> Characterization Of Copper Sintered Interconnects By Transient Thermal Analysis Maximilian Schmid, Sri Krishna Bhogaraju, Gordon Elger, Technische Hochschule Ingolstadt / Germany</p> <p><b>TC2-2</b> Crevice Elimination and Stitch Integrity Improvement on eaded Packages Thru Shifted Lead Neck Design Dolores B. Milo, Gloria B. Manaois, Texas Instruments Philippines / Philippines</p> <p><b>TC2-3</b> Study on Suppression of External Stress Type Tin Whisker by PR Current Method Hiroyuki Iwamoto<sup>1</sup>, Katsuji Nakamura<sup>1</sup>, Kaichi Tsuruta<sup>1</sup>, Osamu Munekata<sup>2</sup>, <sup>1</sup>Senju Metal Industry, <sup>2</sup>Industrial Analysis Service / Japan (15:05)</p>	
15:30 15:40	<b>Break</b>			
15:40	<p><b>TA3: IMPACT Session</b> Chairs: J. Mizuno, Waseda University, A. Shigetou, NIMS</p> <p><b>TA3-1 &lt;Session Invited&gt;</b> Shear Behavior of the High Temperature Pb-Free Solder Joint with Zn-25Sn-xTi-yCu Kwang-Lung Lin, Che-Wei Chang, Min-Ren Chen, National Cheng Kung University / Taiwan</p> <p><b>TA3-2 &lt;Session Invited&gt;</b> Advanced SiP Development for mmWave Antenna in Package Yupo Wang, Siliconware Precision Industries / Taiwan</p> <p><b>TA3-3 &lt;Session Invited&gt;</b> Reliability Issues of Cu-Cu Direct Bonds Chih Chen<sup>1</sup>, Kai-Cheng Shie<sup>1</sup>, Po-Ning Hsu<sup>1</sup>, King-Ning Tu<sup>1,2</sup>, <sup>1</sup>National Yang Ming Chiao Tung University / Taiwan, <sup>2</sup>UCLA / USA United</p>	<p><b>TB3: Advanced Packaging</b> Chairs: T. Aoki, IBM Japan, M. Aoyagi, AIST</p> <p><b>TB3-1 &lt;Session Invited&gt;</b> Highlighting a New Package!! "PhotoMold" Shuzo Akeji, Rising Technologies / Japan</p> <p><b>TB3-2</b> New Ag Pastes Siter Joining on Ag and Cu Surface for High Temperature Application Jinting Jiu, Yoshie Tachibana, Shunsuke Koga, Ryuki Horie, Tomoki Sasaki, Senju metal Industry / Japan</p> <p><b>TB3-3</b> Development of Au/Pt/Ti Multilayers for Wafer-Level Packaging and Residual Gas Gettering Shingo Kariya<sup>1</sup>, Takashi Matsumae<sup>2</sup>, Yuichi Kurashima<sup>2</sup>, Hideki Takagi<sup>2</sup>, Masanori Hayase<sup>1</sup>, Eiji Higurashi<sup>2</sup>, <sup>1</sup>Tokyo University of Science, <sup>2</sup>National Institute of Advanced Industrial Science and Technology / Japan</p>		
16:55				

Room A			
9:00	<b>Keynote Lecture IV: Superconducting Circuits for Quantum Technologies</b> Yasunobu Nakamura, The University of Tokyo / RIKEN Center for Emergent Matter Science Chairs: M. Fujino, AIST, S. Takyu, Lintec		
10:00			
10:00 10:10	<b>Break</b>		
	Room A	Room B	Room C
10:10	<b>FA1: Quantum Computing / Annealer</b> Chair: M. Fujino <b>FA1-1 &lt;Session Invited&gt;</b> Digital Annealer and Its Applications Taisuke Iwai, Fujitsu / Japan <b>FA1-2 &lt;Session Invited&gt;</b> Overview and Present Status of CMOS Annealing Masanao Yamaoka, Hitachi / Japan <b>FA1-3 &lt;Session Invited&gt;</b> Quantum Annealer Using Superconducting Parametric Oscillators Tsuyoshi Yamamoto, NEC / Japan <b>FA1-4 &lt;Session Invited&gt;</b> Combinatorial Optimization Machines Using Quantum or Classical Parametric Oscillators Hayato Goto, Toshiba / Japan	<b>FB1: Epoxy in Innovation</b> Chairs: M. Oda, Printed Electronics Network, M. Inoue, Gunma University <b>FB1-1</b> Development of Flexible Epoxy Film with High Thermal Stability, Especially Suitable for Display and Printed Electronics Applications Iori Doi, Takashi Komori, Noriyasu Yamane, Kotaro Nozawa, Takayoshi Hirai, Mitsubishi Chemical / Japan <b>FB1-2</b> Development of Stretchable Epoxy Film with High Thermal Stability, Especially Suitable for Printed Electronics Applications Iori Doi, Takashi Komori, Noriyasu Yamane, Kotaro Nozawa, Takayoshi Hirai, Mitsubishi Chemical / Japan <b>FB1-3 &lt;Session Invited&gt;</b> Fabrication of Stretchable Electrode with Epoxy Film using Printing Technology Tomohito Sekine <sup>1</sup> , Kosuke Muraki <sup>1</sup> , Itaru Watanabe <sup>2</sup> , Iori Doi <sup>2</sup> , Noriyasu Yamane <sup>2</sup> , Shizuo Tokito <sup>1</sup> , <sup>1</sup> Yamagata University, <sup>2</sup> Mitsubishi Chemical / Japan <b>FB1-4</b> Development of Novel Low Dielectric Epoxy Resin for High Frequency Applications Takaaki Watanabe, Noriyuki Kida, Makoto Takahashi, Takayoshi Hirai, Mitsubishi Chemical / Japan	<b>FC1: High-Speed, Wireless &amp; Components</b> Chairs: K. Yamada, Toshiba, K. Hasegawa, JSR <b>FC1-1 &lt;Session Invited&gt;</b> Wired and Wireless Seamless Networks for Beyond 5G Tetsuya Kawanishi, Waseda University / Japan <b>FC1-2</b> Prototype Evaluation of Antennas with Artificial Magnetic Conductor for Firefighter Support Systems Yusuke Ikuma <sup>1</sup> , Takahiko Yamamoto <sup>1</sup> , Masayuki Mizuno <sup>1</sup> , Yoshifumi Ohmiya <sup>1</sup> , Kohji Koshiji <sup>1</sup> , Yuji Shimizu <sup>2</sup> , Tetsuya Shimizu <sup>2</sup> , <sup>1</sup> Tokyo University of Science, <sup>2</sup> Tokyo Fire Department / Japan <b>FC1-3</b> Impact of Modularization on the Design Process -Case Study of Antenna Design for Smartphones- Atsushi Maeda, Hirofumi Tatsumoto, University of Tsukuba / Japan (11:25)
11:50			
11:50 12:40	<b>Lunch Time</b>		
12:40			
13:40	<b>Poster Session</b>		
13:40 13:50	<b>Break</b>		
	Room A		
13:50	<b>Keynote Lecture V: Progress of Wafer Level Packaging Technology for RF Devices at 5G Era</b> Daquan Yu, Xiamen University Chairs: E. Higurashi, AIST, S. Takyu, Lintec		
14:50			
14:50 15:00	<b>Break</b>		
15:00	<b>ICEP 20th Anniversary Special Lecture: Challenges and Future Directions in the Semiconductor Industry</b> A Stacked Direct Time of Flight Depth Sensor for Automotive LiDAR with SPAD Pixels Oichi Kumagai, Sony Semiconductor Solutions Present and Future of Semiconductor Technology in the Age of Paradigm Shift Akihisa Sekiguchi, Tokyo Electron Chairs: T. Ohba, Tokyo Institute of Technology, E. Higurashi, AIST		
17:10			
17:10 17:20	<b>Introduction of ICEP 2022</b> <b>Closing Remark</b>		

**Poster Session**

**From 12:40-14:40 on May 13 (P01-P07 and Sponsors)**

- P01** Development of Semi-Analytical Formulation for Asymmetric Warp Prediction in Fan-out Reconstitution Process  
K.-S. Chen<sup>1</sup>, Y.-C. Lee<sup>1</sup>, C.-Y. Chen<sup>1</sup>, T.-Y. Chen<sup>2</sup>, D.-L. Chen<sup>2</sup>, David Tarn<sup>2</sup>, <sup>1</sup>National Cheng-Kung University, <sup>2</sup>Advanced Semiconductor Engineering / Taiwan
- P02** The Simulation and Detection of Copper/Polyimide Delamination of Fan-Out Package Trace/Passivation Interface  
Chung-Yu Ke, Liang-Pin Chen, Siliconware Precision Industries / Taiwan
- P03** Analysis of Stress Generated Interface of Trench MIM (Metal-Insulator-Metal) Capacitor Structure  
Eunsol Jo, Jung-Rae Park, Cheong-Ha Jung, Gu-Sung Kim, Electronic Package Research Center / Korea
- P04** Evaluation of Dispersibility of Silver Nanoparticle Ink by TEM and NMR  
Hirota Shioji<sup>1</sup>, Kazuo Kimura<sup>1</sup>, Shin Inamoto<sup>1</sup>, Naoki Muraki<sup>1</sup>, Daisuke Kumaki<sup>2</sup>, Shizuo Tokito<sup>2</sup>, <sup>1</sup>Toray Research Center, <sup>2</sup>Yamagata University / Japan
- P05** Superhydrophobic Surface Based on Silane Coating on Silicon-Based Electrospun Nanostructures  
Cho-Liang Chung, ChunWei Cheng, Cheng-Ying Tsai, Yu-Ching Chao, Wei-Hao Chen, I-Shou University / Taiwan
- P06** Effects of Moisture and Oxygen on the Morphology Evolution of Electrospinning Woven  
Sian-Sheng Li, Huai-You Lee, Yi-Min Lin, Cho-Liang Chung, I-Shou University / Taiwan
- P07** Accuracy Assessment of Quantification Method of Cellulose Nano-Fiber in Nickel Plating Film Using Image Analysis  
Makoto Iioka, Ikuo Shohji, Tatsuya Kobayashi, Gunma University / Japan

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**From 12:40-13:40 on May 14 (P08-P14 and Sponsors)**

- P08** Materials Informatics Technology for Using Eco-Friendly Materials  
Tomio Iwasaki, Hitachi / Japan
- P09** Analysis of Interfacial Conductivity Variations of Copper-Filled Electrically Conductive Adhesives During Environmental Tests  
Daisuke Otajima, Yuki Saito, Masahiro Inoue, Gunma University / Japan
- P10** Structural Control of PEDOT: PSS Thin Films Using Non-Ionic Surfactants for Enhancing Stretchability  
Kaito Oozutsumi, Masahiro Inoue, Gunma University / Japan
- P11** Analysis of Reflection Characteristics and Radiation Efficiency on Thickness and Conductivity of Monopole Antenna Using Transparent Conductive Film  
Yuri Yamada<sup>1</sup>, Fukuro Koshiji<sup>1</sup>, Yoji Yasuda<sup>1</sup>, Takayuki Uchida<sup>1</sup>, Katsumi Yamada<sup>1</sup>, Kohji Koshiji<sup>2</sup>, <sup>1</sup>Tokyo Polytechnic University, <sup>2</sup>Tokyo University of Science / Japan
- P12** Investigation of Broadband Circularly-Polarized Unbalanced Dipole Antenna Consisting of Semicircular and Trapezoidal Elements  
Hironori Takahashi<sup>1</sup>, Fukuro Koshiji<sup>1</sup>, Kohji Koshiji<sup>2</sup>, <sup>1</sup>Tokyo Polytechnic University, <sup>2</sup>Tokyo University of Science / Japan
- P13** Via Resonance Amplitude Control  
Vinod Arjun Huddar, Rambus / India
- P14** Development of Novel BN Filler for High Thermal Conductivity Packaging Material  
Shota Daiki, Kyoichi Fujinami, Seiji Imazumi, Saiko Fujii, Isao Masada, Yukihiko Kanechika, Teruhiko Nawata, Masahide Ueda, Tokuyama Corporation / Japan

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# On-Demand Session (Streaming Period: May 12-25)

## OD1: Advanced Packaging

### OD1-1

Development of Leadframe for Quad Flat No-lead Package

Mei-Ling Wu, Che-Wei Kang, National Sun Yat-sen University / Taiwan

### OD1-2

Evaluation of Direct Metallization Technology Plating Properties with Excellent Material Selectivity

Takuya Komeda, Tetsuji Ishida, Hisamitsu Yamamoto, C. Uyemura / Japan

### OD1-3

Development of High Reliability Joint of Sn-Bi Solder for 2.3D Organic Package

Shota Miki, Koyuki Kawakami, Kei Murayama, Kiyoshi Oi, SHINKO ELECTRIC INDUSTRIES / Japan

### OD1-4

Mechanical Reliability Analysis of Dual Side Molding SiP Module

Tse-Wei Liao, Wei-Hong Lai, Hsin-Chih Shih, Dao-Long Chen, David Tarn, CP Hung, Advanced Semiconductor Engineering / Taiwan

### OD1-5

Copper sintered Si3N4 Power Modules in Thermal Shock Tests

Thomas Blank<sup>1</sup>, Hongpeng Zhang<sup>2</sup>, Helge Wurst<sup>1</sup>, Benjamin Leyrer<sup>1</sup>, Felix Steiner<sup>1</sup>, Dai Ishikawa<sup>2</sup>, Udo Geckeke<sup>1</sup>, Ivan Peric<sup>1</sup>, <sup>1</sup>Karlsruhe Institute of Technology / Germany, <sup>2</sup>Showa Denko Materials / Japan

### OD1-6

Low Temperature Bonding with Wafer Level Nanocrystalline Cu Film

Wei-Lan Chiu, Chia-Wen Chiang, Hsiang-Hung Chang, Industrial Technology Research Institute / Taiwan

### OD1-7

Novel Approach of Die Attach Technology for SiC Power Module by Pure Al Thin Film Bonding

Chuantong Chen, Katsuki Sugauma, Osaka University / Japan

### OD1-8

Prediction of Fan-Out Level Packaging Warpage Using PSO-based Modified Convolutional Neural Network Model with Laplacian Filter

G. R. Huang, M. Y. Chen, K. N. Chiang, National Tsing Hua University / Taiwan

### OD1-9

Electromigration Improvement by Graphene on Cu Wire for Next Generation VLSI

Y. T. Hung<sup>1</sup>, J. Z. Huang<sup>1,2</sup>, H. H. Chang<sup>1</sup>, K. P. Huang<sup>1</sup>, O. H. Lee<sup>1</sup>, W. L. Chiu<sup>1</sup>, H. J. Jian<sup>1</sup>, K. C. Huang<sup>1</sup>, W. C. Lo<sup>1</sup>, J. S. Hu<sup>1</sup>, C. I. Wu<sup>1,2</sup>, <sup>1</sup>Industrial Technology Research Institute, <sup>2</sup>National Taiwan University / Taiwan

### OD1-10

A Study of Factors Affecting Process-induced Warpage Behavior of Flip Chip Package on Package

Yi-Huang Chen, Ling-Ching Tai, Yan-Cheng Liu, Hsien-Chie Cheng, Feng Chia University / Taiwan

### TB3-3 (Pre-recorded video for live session presentation)

Development of Au/P/Ti Multilayers for Wafer-Level Packaging and Residual Gas Gettering

Shingo Kariya<sup>1</sup>, Takashi Matsumae<sup>2</sup>, Yuichi Kurashima<sup>2</sup>, Hideki Takagi<sup>2</sup>, Masanori Hayase<sup>2</sup>, Eiji Higurashi<sup>2</sup>, <sup>1</sup>Tokyo University of Science, <sup>2</sup>National Institute of Advanced Industrial Science and Technology / Japan

## OD2: Quality, Modeling, and Reliability

### OD2-1

Experimental Investigation of Ultra-Thin Silicon Wafers Warpage

Mei Ling Wu, Tzu Chi Tseng, National Sun Yat-sen University / Taiwan

### OD2-2

Study of Substrate Materials on Bias-HAST Reliability of Fine Pitch FCBGAs Package

Yu-Cheng Pai, Wen-Yu Teng, Hsuan-Hao Mi, Liang-Yih Hung, Andrew Kang, Yu-Po Wang, Siliconware Precision Industries / Taiwan

### OD2-3

Prognostic Health Monitoring Method For Thermal Fatigue Failure Of Power Module Solder Joints Using The Grain Boundary Sliding Model

Hideaki Uehara, Tomoko Monda, Akira Kano, Tomoya Fumikura, Kenji Hirohata, Toshiba / Japan

### OD2-4

White X-ray Nanodiffraction Study of Allotropic Phase Transformation of Hexagonal- into Monoclinic-Cu<sub>6</sub>Sn<sub>5</sub>

Pei-Tzu Lee<sup>1</sup>, Wan-Zhen Hsieh<sup>2</sup>, Cheng-Yu Lee<sup>3</sup>, C. R. Kao<sup>1</sup>, Cheng-En Ho<sup>3</sup>, <sup>1</sup>National Taiwan University, <sup>2</sup>National Synchrotron Radiation Research Center, Taiwan, <sup>3</sup>Yuan Ze University / Taiwan

### OD2-5

The Voids Growth Path on Sn-Ag Thin Film Under High Current Density

Zhi Jin<sup>1</sup>, Yu-An Shen<sup>1</sup>, Yang Zuo<sup>2</sup>, S.H. Mannan<sup>2</sup>, Hiroshi Nishikawa<sup>1</sup>, <sup>1</sup>Osaka University / Japan, <sup>2</sup>King's College London / UK

### OD2-6

Detection Of Die Attach Defects Through Rapid Thermal Transient Tests

Voon Hon Wong<sup>1</sup>, Andras Vass-Varnai<sup>2</sup>, Antonio Caruso<sup>3</sup>, Tomoaki Hara<sup>4</sup>, Alvin Hsu<sup>5</sup>, Gang Wang<sup>5</sup>, <sup>1</sup>Siemens Digital Industry Software / Singapore, <sup>2</sup>Siemens Digital Industry Software / USA, <sup>3</sup>Siemens Digital Industry Software / Italy, <sup>4</sup>Siemens Digital Industry Software / Japan, <sup>5</sup>Siemens Digital Industry Software / Greater China

### OD2-7

Detectable Resistance Increase of Open Defects in Assembled PCBs by Quiescent Currents Through Embedded Diodes

Yuya Okumoto<sup>1</sup>, Hiroyuki Yotsuyanagi<sup>1</sup>, Masaki Hashizume<sup>1</sup>, Shyue-Kung Lu<sup>2</sup>, <sup>1</sup>Tokushima University / Japan, <sup>2</sup>National Taiwan University of Science and Technology / Taiwan

## OD3: Interconnections

### OD3-1

Morphology and Mechanical Property of Cu Pillar Formed by Sintered Cu Nanoparticles for the Plating-Free Bumping Process

Chinami Marushima<sup>1</sup>, Toyohiro Aoki<sup>1</sup>, Sayuri Kohara<sup>1</sup>, Ryota Yamaguchi<sup>2</sup>, Nobuhiro Sekine<sup>2</sup>, Kenichi Yatsugi<sup>2</sup>, Kuniaki Sueoka<sup>1</sup>, Takashi Hisada<sup>1</sup>, <sup>1</sup>IBM Japan, <sup>2</sup>DIC / Japan

### WB1-1 (Pre-recorded video for live session presentation)

Pressureless and Low Temperature Direct Bonding on Si, SiC and GaN via Ag Paste Sinter-joining

Zheng Zhang, Chuantong Chen, Aiji Suetake, Ming-Chun Hsieh, Aya Iwaki, Katsuki Sugauma, Osaka University / Japan

### WB2-1 (Pre-recorded video for live session presentation)

Reliable Joint Material by Sn-Cu-Ni IMC Fine Particles

Shigenobu Sekine<sup>1</sup>, Hiroaki Ikeda<sup>1</sup>, Shigeo Arai<sup>2</sup>, <sup>1</sup>Napra, <sup>2</sup>Nagoya University / Japan

### WB2-2 (Pre-recorded video for live session presentation)

A Technique to Mount Narrow-Pitch Micro Solder Balls

Shunichi Haraguchi<sup>1</sup>, Chisato Oyama<sup>1</sup>, Kotaro Usuda<sup>2</sup>, Hideki Ikeda<sup>1</sup>, <sup>1</sup>KOMORI, <sup>2</sup>SERIA ENGINEERING / Japan

## OD4: Materials and Processing

### OD4-1

Development of Novel Bevel Profile for Wafer-level Stacking Technology

Tatsuhiko Aoki<sup>1,2</sup>, Manabu Hirasawa<sup>2</sup>, Koji Izunome<sup>2</sup>, Takayuki Ohba<sup>1</sup>, <sup>1</sup>Tokyo Institute of Technology, <sup>2</sup>Global Wafers Japan / Japan

### OD4-2

The Control of Material Surface Condition for Plasma Technology to Fabricate Advanced Packaging

Daisuke Hirohata, Yasuhiro Morikawa, Tsuyoshi Kagami, Takashi Kurimoto, Kazumasa Horita, Ryuichiro Kamimura, ULVAC / Japan

### OD4-3

High Aspect/Narrow Pitch Substrate Wiring and Bump Formation Using Imprinting Technology for Low Temperature Flip Chip Bonding

Hiroshi Komatsu<sup>1</sup>, Daisuke Sakai<sup>1</sup>, Nozomi Shimoishizaka<sup>1</sup>, Toshihiro Yamada<sup>2</sup>, <sup>1</sup>CONNECTEC JAPAN, <sup>2</sup>Industrial Research Institute of Niigata Prefecture / Japan

### OD4-4

Novel Isotropic Low Dk/Df film for 5G Application

Meiten Koh<sup>1</sup>, Masayuki Shimura<sup>1</sup>, Shoya Sekiguchi<sup>2</sup>, Shoko Mishima<sup>2</sup>, Nobuhiro Ishikawa<sup>2</sup>, Toshiyuki Ogata<sup>2</sup>, <sup>1</sup>Taiyo Ink MFG., <sup>2</sup>Taiyo Holdings / Japan

### OD4-5

Effects of Epoxy Molding Compound on Managed NAND(mNAND) Package Strain Enhancement

Joyce Chen<sup>1</sup>, Vance Liu<sup>1</sup>, Lewis Lin<sup>1</sup>, Min Chung<sup>1</sup>, Chong Leong, Gan<sup>1</sup>, Hem Takiar<sup>2</sup>, <sup>1</sup>Micron Technology / Taiwan, <sup>2</sup>Micron Technology / USA

### OD4-6

Surface Modification of Tetra-needle like ZnO (F-ZnO) and Characterization of Interface Between Sn1.0Ag0.5Cu and NiO Decorated TZnO

Fupeng Huo<sup>1</sup>, Keke Zhang<sup>2</sup>, Hiroshi Nishikawa<sup>1</sup>, <sup>1</sup>Osaka University / Japan, <sup>2</sup>Henan University of Science and Technology / China



## OD4-7

Better Warpage Control by Using Low Temperature Solder for Large FCBGA Application  
Da-Sheng Lai, Jackson Lee, Joe Huang, Yu-Po Wang, Siliconware Precision Industries / Taiwan

## OD4-8

Post Mechanical Shock Test Failure Analysis on Mixed SnAgCu-BiSn BGA Solder Joints  
Raiyo Aspandiar<sup>1</sup>, Kei Murayama<sup>2</sup>, Pubudu Goonetilleke<sup>3</sup>, Jagadeesh Radhakrishnan<sup>1</sup>, Haley Fu<sup>3</sup>, <sup>1</sup>Intel / USA, <sup>2</sup>Shinko Electric Industries / Japan, <sup>3</sup>NEMI / China

## OD4-9

Effect of 4.0 mass % Cu Addition on Microstructure and Mechanical Properties of In-48Sn Alloy  
Duy Le Han<sup>1,2</sup>, Byungho Park<sup>1</sup>, Hiroshi Nishikawa<sup>1</sup>, <sup>1</sup>Osaka University / Japan, <sup>2</sup>Hanoi University of Science and Technology / Vietnam

## OD4-10

High-Performance Film-Type Thermal Interface Material Containing Vertically Aligned Carbon Nanofibers  
Wen-Yu Teng, Hsin-Ming Tseng, Liang-Yi Hung, Yu-Po Wang, Siliconware Precision Industries / Taiwan

### TB1-4 (Pre-recorded video for live session presentation)

Fine Pitch Bumping and Flip Chip Joining with Sn-Bi Based Solders by Injection Molded Solder Technology  
Toyohiro Aoki<sup>1</sup>, Katsuhiro Yoshida<sup>2</sup>, Koki Nakamura<sup>2</sup>, Takashi Hisada<sup>1</sup>, Kozo Fujimoto<sup>2</sup>, Shinji Fukumoto<sup>2</sup>, <sup>1</sup>IBM Japan, <sup>2</sup>Osaka University / Japan

### TB2-3 (Pre-recorded video for live session presentation)

X-ray Radiolysis-Induced-Photochemical Reaction at Interface Between Liquid and Substrate  
S. Saegusa<sup>1</sup>, N. Akamatsu<sup>1</sup>, I. Sakurai<sup>2</sup>, I. Okada<sup>3</sup>, Y. Utsumi<sup>1</sup>, A. Yamaguchi<sup>1</sup>, <sup>1</sup>University of Hyogo, <sup>2</sup>Nagoya University, <sup>3</sup>Aichi Synchrotron Radiation Center / Japan

## OD5: Emerging Technologies

### OD5-1

Frequency Characteristics of Ultrathin and Transparent Organic Electrochemical Transistors with 1- $\mu$ m-Thick Parylene Lamination  
Kazuya Nishimura<sup>1</sup>, Teppei Araki<sup>1,2</sup>, Ashuya Takemoto<sup>2</sup>, Mihoko Akiyama<sup>1</sup>, Kazuki Kiriya<sup>1</sup>, Yuko Kasai<sup>2</sup>, Naoko Kurihira<sup>1</sup>, Takafumi Uemura<sup>1,2</sup>, Tsuyoshi Sekitani<sup>1,2</sup>, <sup>1</sup>Osaka University, <sup>2</sup>AIST-Osaka University / Japan

### OD5-2

Electronic Band-Engineering of a Dumbbell-shaped Graphene Nanoribbon by the Application of Uniaxial Tensile Strain  
Jowesh Avisheik Goundar, Qinqiang Zhang, Ken Suzuki, Hideo Miura, Tohoku University / Japan

### OD5-3

Experimental Demonstration of Wireless Energy Harvesting for ZigBee Wireless Communication  
Mohamed M. Mansour<sup>1,3</sup>, Masaya Murakami<sup>2</sup>, Shota Torigoe<sup>2</sup>, Shuya Yamamoto<sup>1</sup>, Haruichi Kanaya<sup>1</sup>, <sup>1</sup>Kyushu University, <sup>2</sup>SEIKO ELECTRIC / Japan, <sup>3</sup>Electronics Research Institute / Egypt

### WC1-2 (Pre-recorded video for live session presentation)

Battery Less Soil Moisture Sensors for Strawberry Seedlings  
Haruichi Kanaya<sup>1</sup>, Osamu Takiguchi<sup>2</sup>, Shunsuke Uto<sup>2</sup>, Katsumi Shimomura<sup>3</sup>, <sup>1</sup>Kyushu University, <sup>2</sup>ALSENS, <sup>3</sup>Fukuoka Agriculture and Forestry Research Center / Japan

### WC2-2 (Pre-recorded video for live session presentation)

Development of Power Management System for RF Energy Harvester  
Masaya Murakami<sup>1</sup>, Mohamed M. Mansour<sup>2</sup>, Shota Torigoe<sup>2</sup>, Shuya Yamamoto<sup>2</sup>, Haruichi Kanaya<sup>1</sup>, <sup>1</sup>SEIKO ELECTRIC, <sup>2</sup>Kyushu University / Japan

## OD6: High-Speed, Wireless & Components

### OD6-1

Silver-Seed Cu-Wirings for High-Speed Transmission  
Norimasa, Fukazawa, Wataru Fujikawa, Akinori Furutani, Shota Niibayashi, Hiroyuki Hagiwara, Jun Shirakami, DIC / Japan

## OD7: Optoelectronics

### OD7-1

Realizing Low Optical Crosstalk, Wide Color Gamut Mini-LED Displays via Laser-Patterned Quantum Dots Color Conversion Layer  
Yuanjie Cheng, Jeffery C. C. Lo, Xing Qiu, S. W. Ricky Lee, Hong Kong University of Science & Technology / Hong Kong

## OD8: Power Electronics

### OD8-1

Effect of Sintering Density on Thermal Reliability by Non-Pressure Sintering Die-Attach  
Ryo Kato, Masatoshi Okuda, Suguru Hashidate, Takamichi Mori, Junichiro Minami, Tetsuo Sakurai, Taro Fukui, OSAKA SODA / Japan

### OD8-2

Design Optimization of Copper Patterns and Location of Power Semiconductors and Terminals  
Yusuke Abe<sup>1</sup>, Akira Hirao<sup>2</sup>, Ryoichi Kato<sup>2</sup>, Yoshinari Ikeda<sup>2</sup>, Victor Parque<sup>1</sup>, Muhammad Khairi Faiz<sup>1</sup>, Makoto Yoshida<sup>1</sup>, Tomoyuki Miyashita<sup>1</sup>, <sup>1</sup>Waseda University, <sup>2</sup>Fuji Electric / Japan

### OD8-3

The Effect of Solid-state Nanoporous Cu Bonding for Power Device  
Byungho Park<sup>1</sup>, Duy Le Han<sup>1,3</sup>, Mikiko Saito<sup>2</sup>, Jun Mizuno<sup>2</sup>, Hiroshi Nishikawa<sup>1</sup>, <sup>1</sup>Osaka University, <sup>2</sup>Waseda University / Japan, <sup>3</sup>Hanoi University of Science and Technology / Vietnam

### WC3-1 (Pre-recorded video for live session presentation)

Packaging of (650 V, 150 A) GaN HEMT with Low Parasitics and High Thermal Performance  
Shengchang Lu, Tianyu Zhao, Rolando Burgos, Guo-Quan Lu, Virginia Tech / USA

### WA3-2 (Pre-recorded video for live session presentation)

Low Pressure Subcooled Boiling in a Compact Vessel for Cooling Technology  
Noriyuki Unno, Kazuhisa Yuki, Risako Kibushi, Koichi Suzuki, Sanyo-Onoda City University / Japan

## OD9: Thermal Management

### OD9-1

Relationships of Design Parameters and the Cooling Performance of the Spiral-Fin Heatsink  
Shingo Otake<sup>1</sup>, Motohito Hori<sup>2</sup>, Ryoichi Kato<sup>2</sup>, Yoshinari Ikeda<sup>2</sup>, Victor Parque<sup>1</sup>, Muhammad Khairi Faiz<sup>1</sup>, Makoto Yoshida<sup>1</sup>, Tomoyuki Miyashita<sup>1</sup>, <sup>1</sup>Waseda University, <sup>2</sup>Fuji Electric / Japan

### OD9-2

Investigation of Heat Transfer in 3D Packaging for Practical-scale Quantum Annealing Machines  
Wei Feng, Katsuya Kikuchi, Mutsuo Hidaka, Hirotake Yamamori, Yuuki Araga, Kazumasa Makise, Shiro Kawabata, National Institute of Advanced Industrial Science and Technology / Japan

### WA3-3 (Pre-recorded video for live session presentation)

Parameter Identification of Distributed Thermal Network for Surface Mount Type Power Semiconductor Packages  
Koji Nishi, Ashikaga University / Japan

### WA3-4 (Pre-recorded video for live session presentation)

Room-Temperature Bonding of AlN Ceramic and Si Semiconductor Substrates for Improved Thermal Management  
Takashi Matsumae<sup>1</sup>, Yuichi Kurashima<sup>2</sup>, Hideki Takagi, Kazunori Nishizono<sup>2</sup>, Tsutomu Amano<sup>2</sup>, Eiji Higurashi<sup>1</sup>, <sup>1</sup>National Institute of Advanced Industrial Science and Technology, <sup>2</sup>MARUWA / Japan